



US00D410080S

United States Patent [19]

Heidsiek et al.

[11] **Patent Number: Des. 410,080**

[45] **Date of Patent: ** May 18, 1999**

[54] **DIAGNOSTIC TESTING INSTRUMENT**

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[73] Assignee: **Gen-Probe Incorporated**, San Diego, Calif.

[**] Term: **14 Years**

[21] Appl. No.: **29/078,352**

[22] Filed: **Oct. 13, 1997**

[51] **LOC (6) Cl. 29-02**

[52] **U.S. Cl. D24/107**

[58] **Field of Search D24/107, 185, D24/186, 234; 128/630, 906; 422/50, 62, 64; 436/43-45, 55; 364/140.09, 497, 480, 180**

[56] **References Cited**

U.S. PATENT DOCUMENTS

D. 282,203 1/1986 Leonard et al. D24/107

D. 326,908 6/1992 Gilbert et al. D24/107
D. 369,564 5/1996 Whitby et al. D24/234
5,147,610 9/1992 Watanabe et al. 422/64
5,270,210 12/1993 Weyrauch et al. 422/64 X

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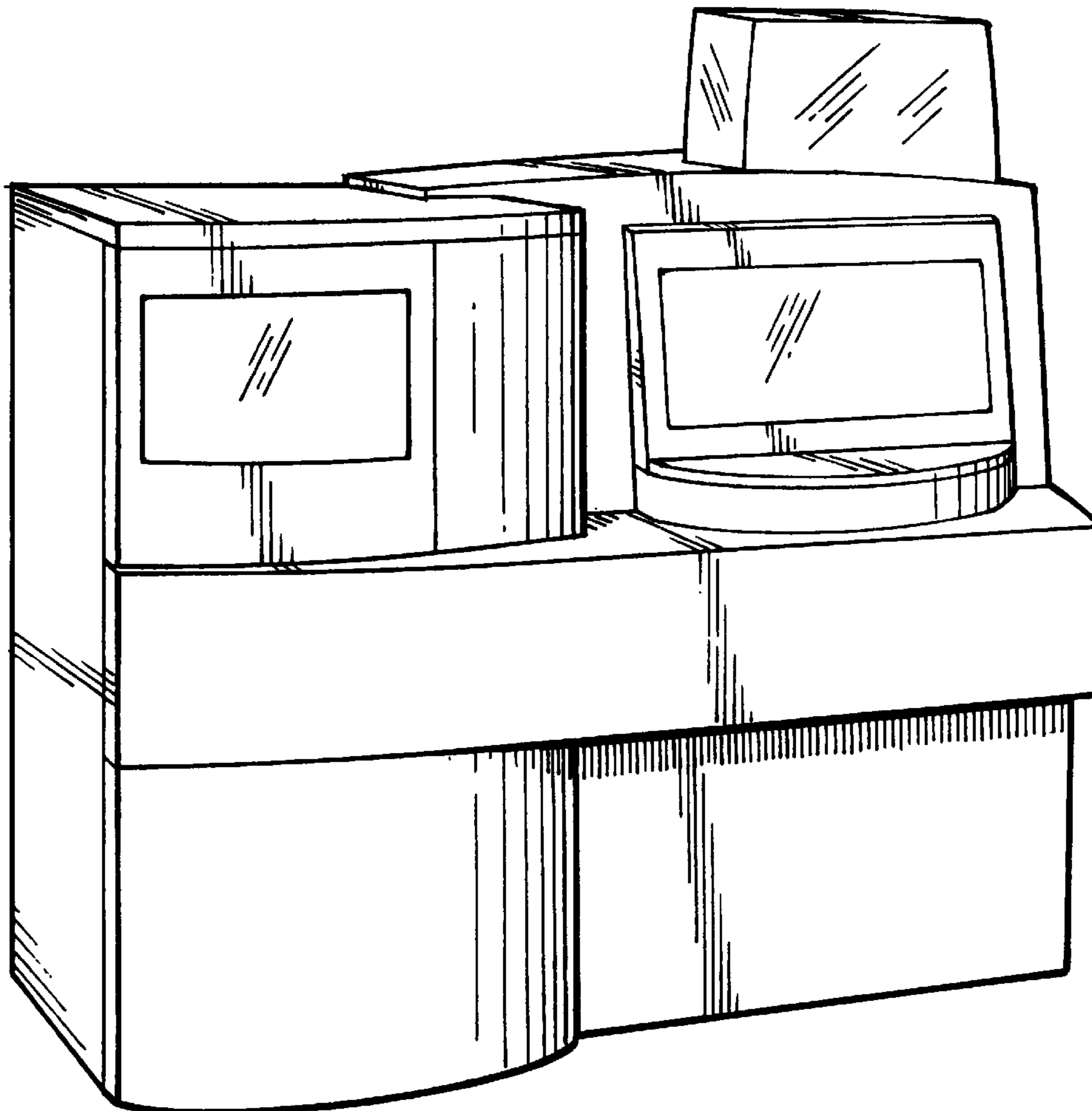
[57] **CLAIM**

The design for a diagnostic testing instrument, as shown and described.

DESCRIPTION

FIG. 1 is a top, front and left side perspective view of our new design for a diagnostic testing instrument;
FIG. 2 is a top, front and right side perspective view thereof;
FIG. 3 is a front elevation view thereof;
FIG. 4 is a plan view thereof;
FIG. 5 is a rear elevation view thereof;
FIG. 6 is a left side elevation view thereof; and,
FIG. 7 is right side elevation view thereof.

1 Claim, 5 Drawing Sheets



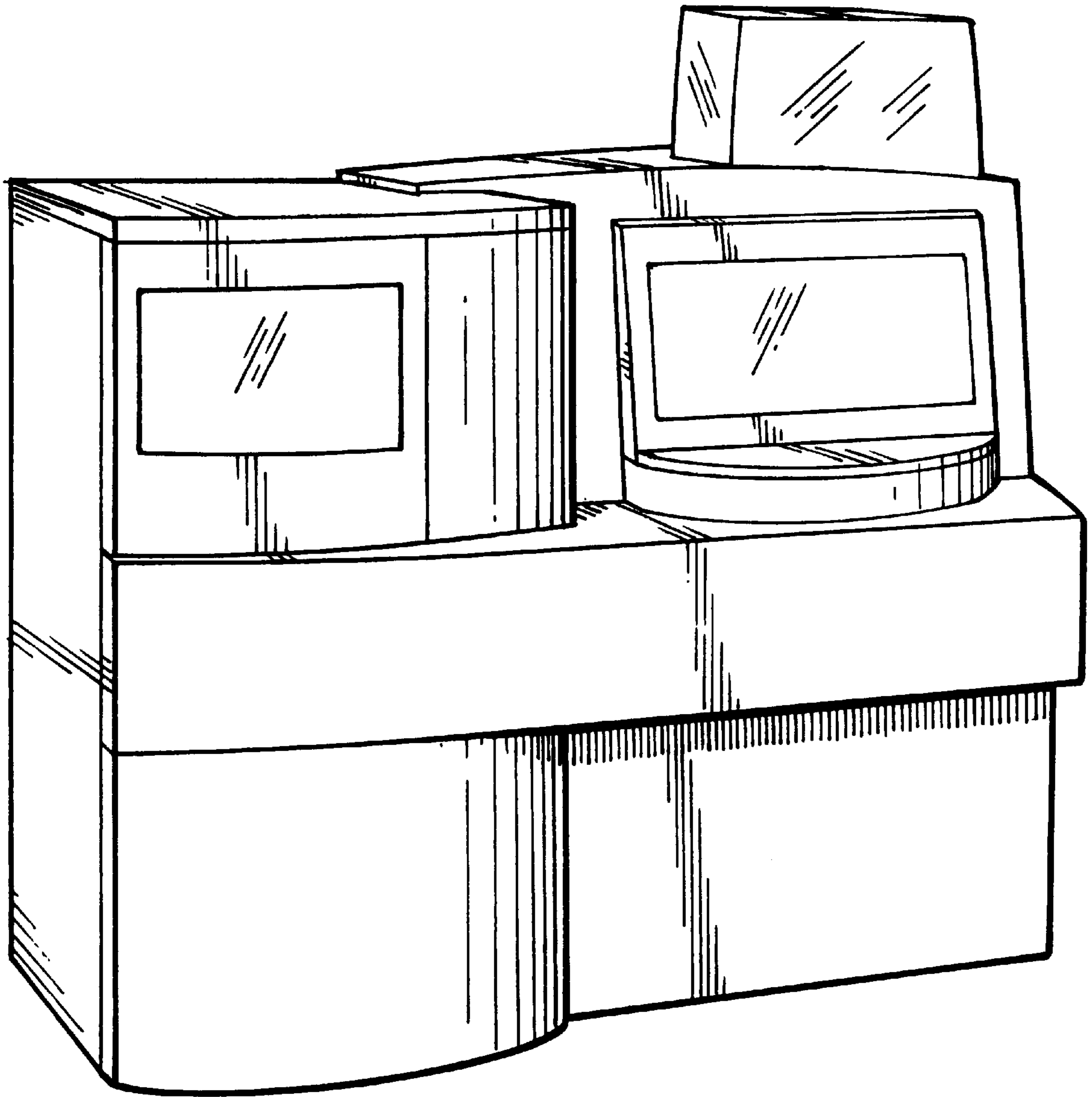


Fig. 1

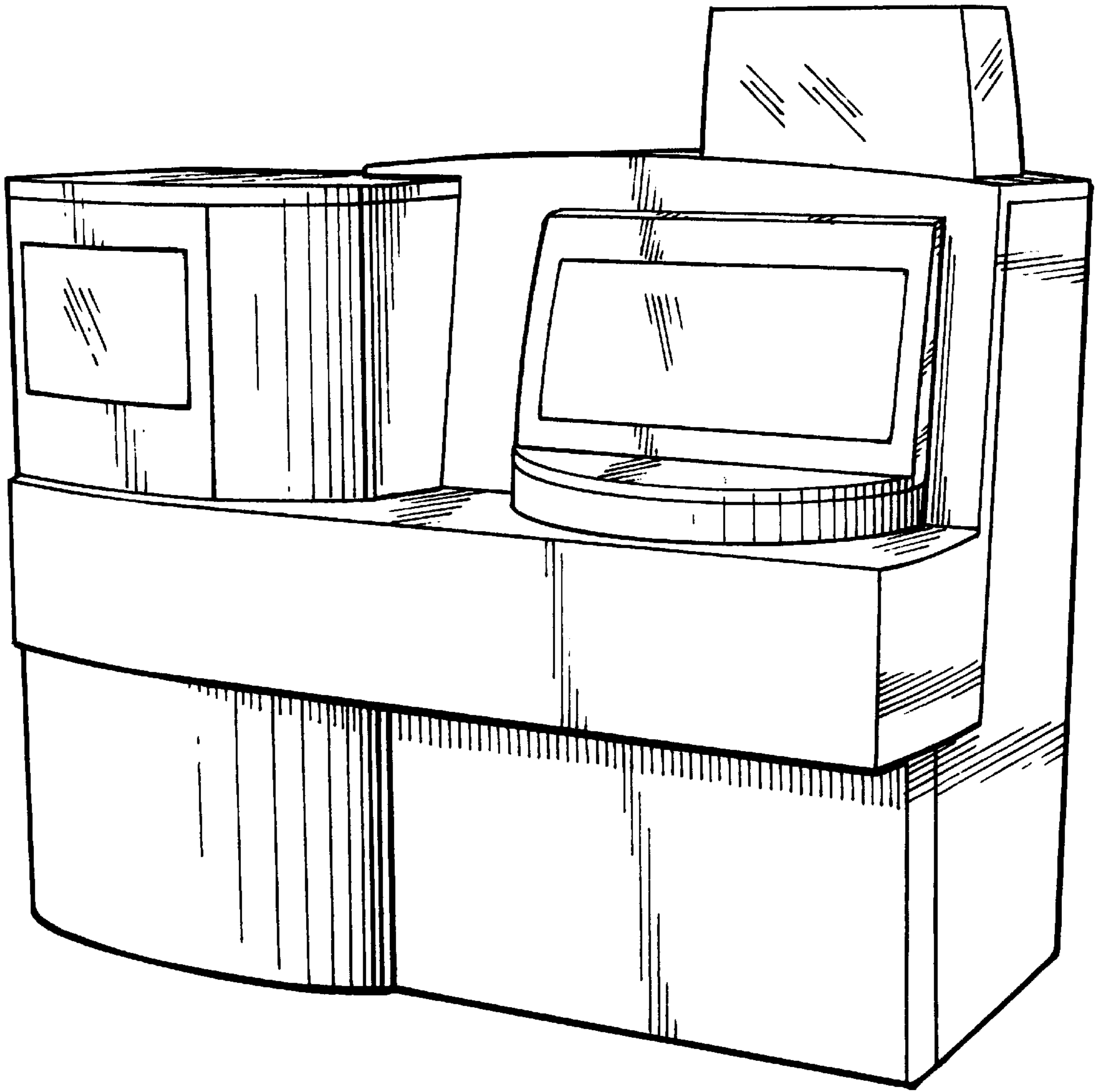


Fig. 2

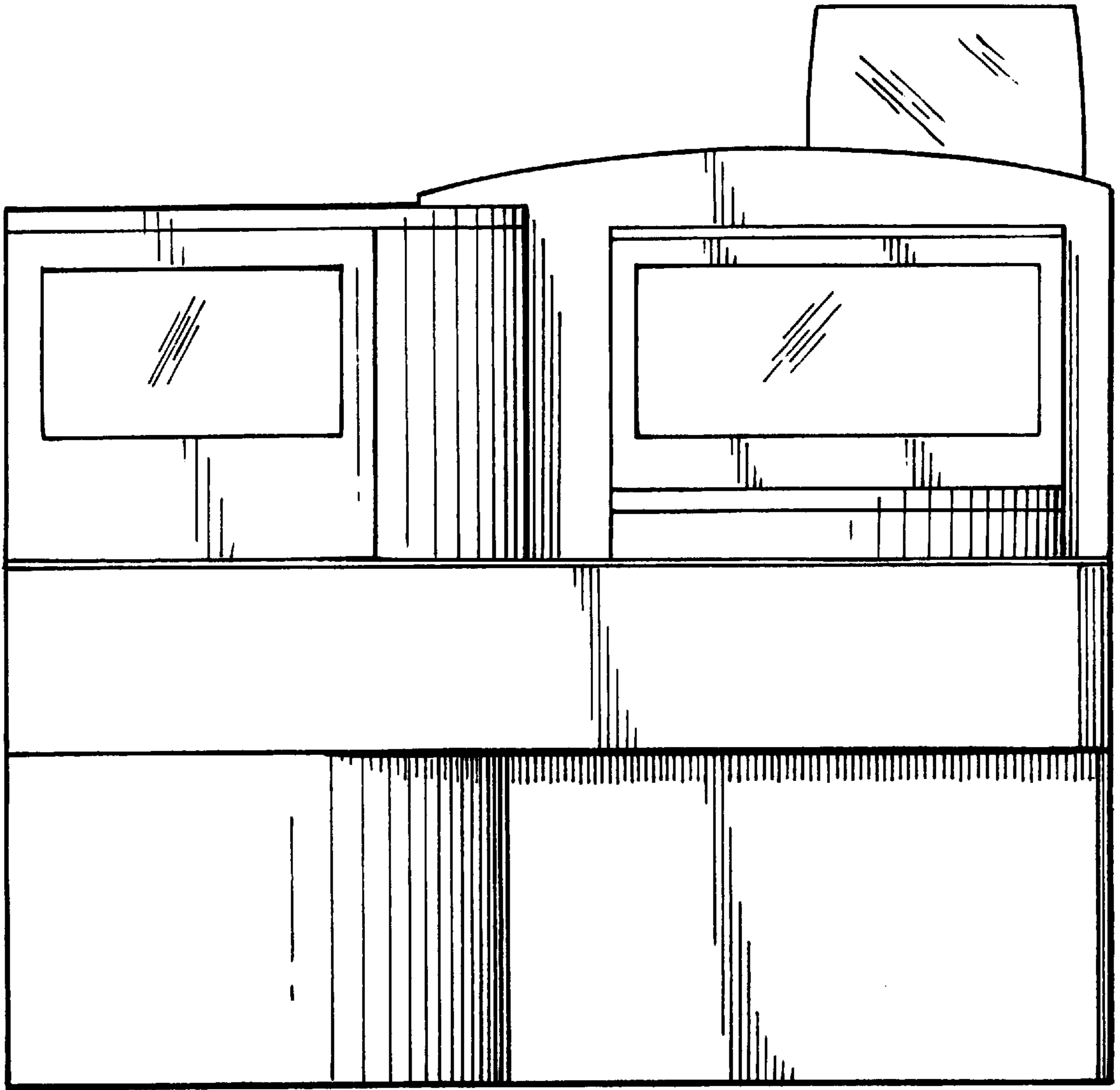


Fig. 3

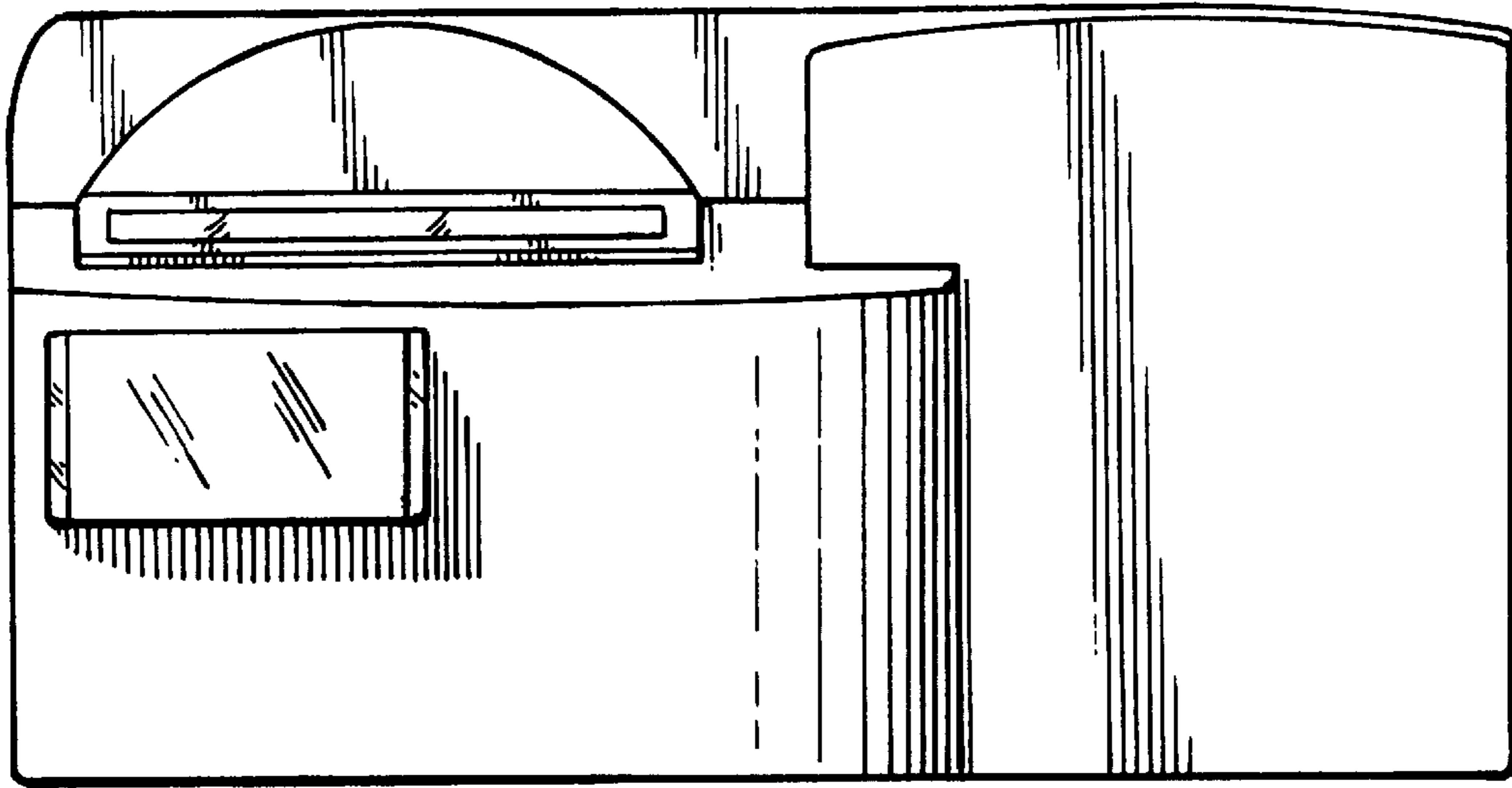


Fig. 4

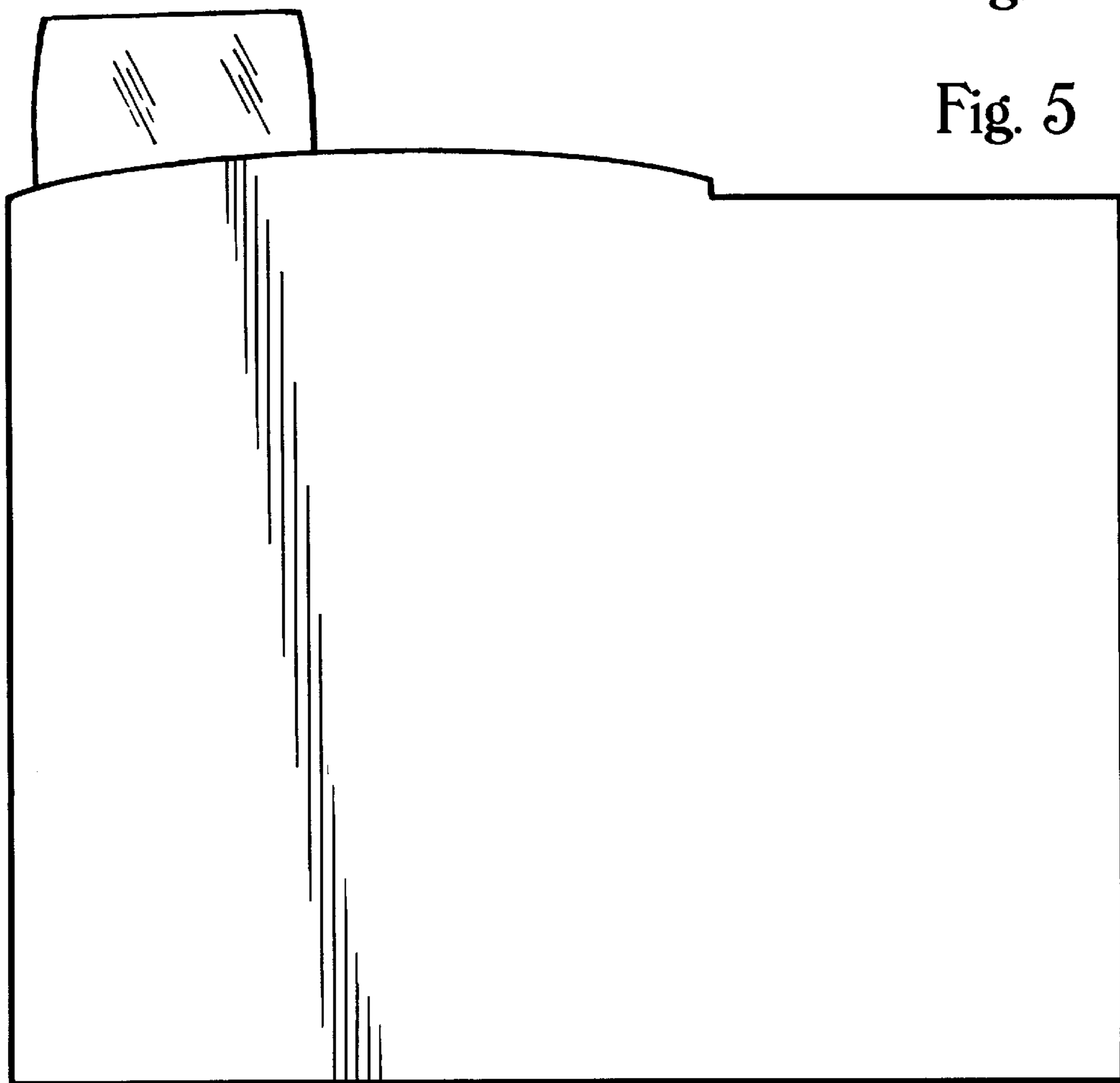


Fig. 5

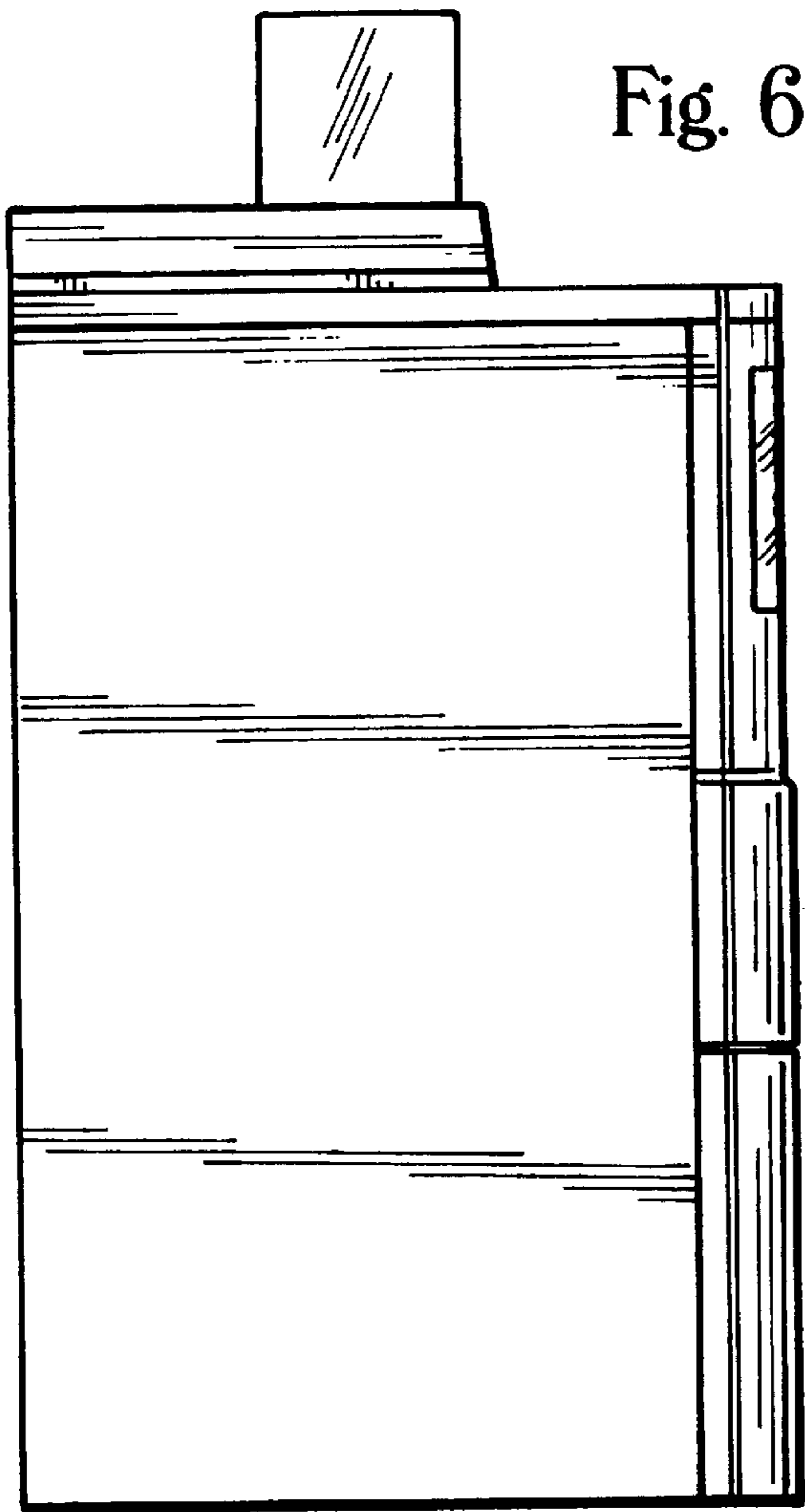


Fig. 6

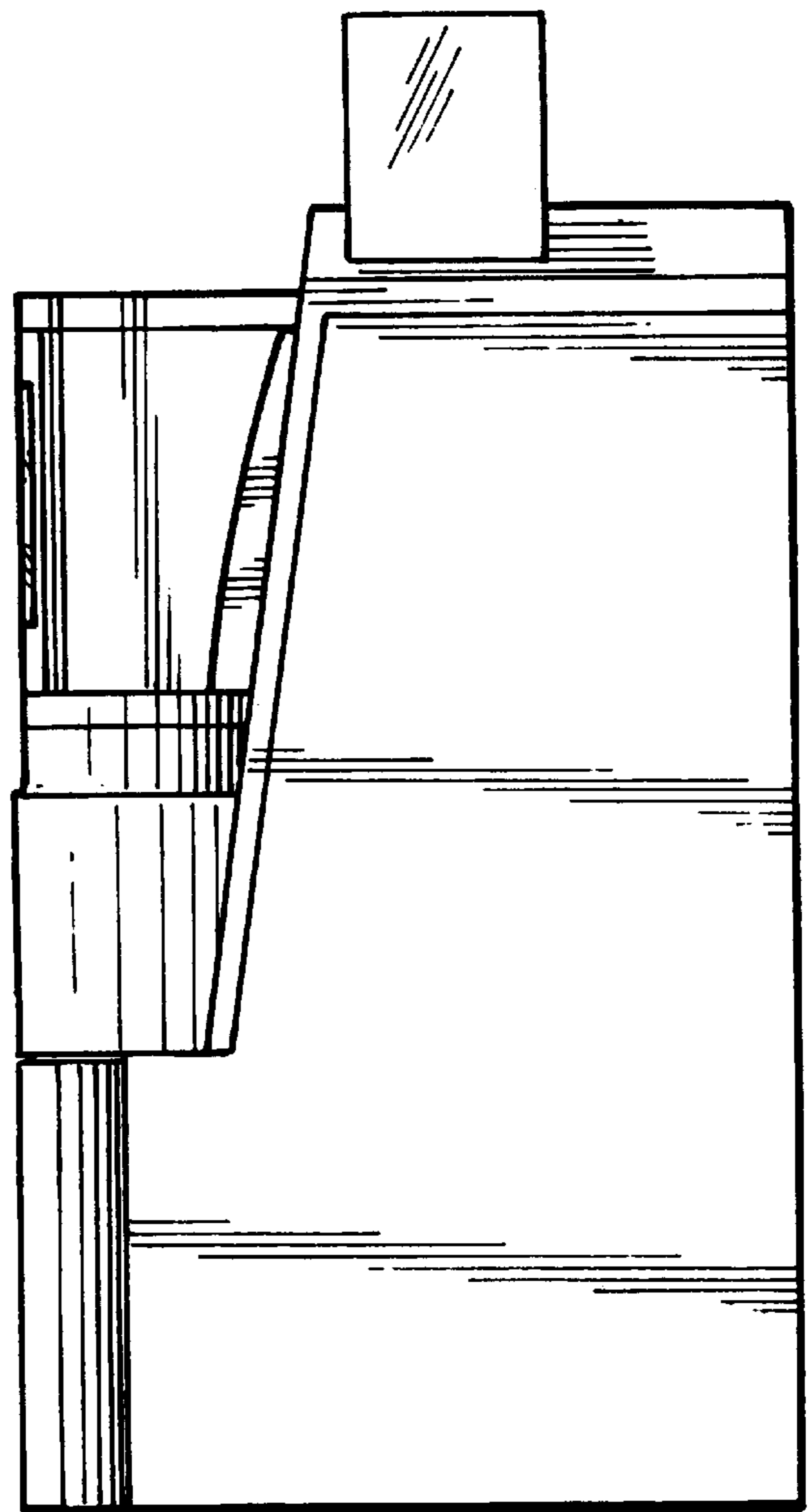


Fig. 7